FAIRCHILD SEMICONDUCTOR TM

June 1999

Si4936DY*

Dual N-Channel Enhancement Mode MOSFET

General Description

These N-Channel Enhancement Mode MOSFETs are produced using Fairchild Semiconductor's advance process that has been especially tailored to minimize on-state resistance and yet maintain superior switching performance.

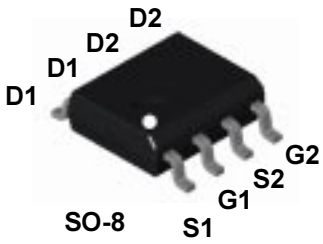
These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

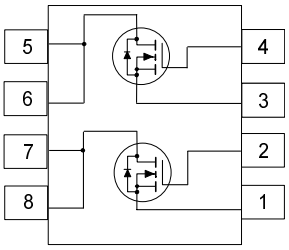
Features

- 5.8 A, 30 V. $R_{DS(ON)}$ = 0.037 Ω @ V_{GS} = 10 V
  $R_{DS(ON)}$ = 0.055 Ω @ V_{GS} = 4.5 V
- Low gate charge.
- Fast switching speed.
- High power and current handling capability.

Applications

- Battery switch
- Load switch
- Motor controls





Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V_{DSS}	Drain-Source Voltage		30	V
V_{GSS}	Gate-Source Voltage		±20	V
I_D	Drain Current - Continuous	(Note 1a)	5.8	A
	- Pulsed		30	
P_D	Power Dissipation for Single Operation		2.0	W
	Power Dissipation for Single Operation	(Note 1a)	1.6	
		(Note 1b)	1	
		(Note 1c)	0.9	
T_J, T_{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

Package Outlines and Ordering Information

Device Marking	Device	Reel Size	Tape Width	Quantity
4936	SI4936DY	13"	12mm	2500 units

* Die and manufacturing source subject to change without prior notification.

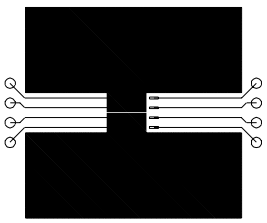
Electrical Characteristics

T_A = 25°C unless otherwise noted

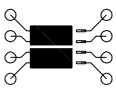
Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	V_{GS} = 0 V, I_D = 250 µA	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = 250 µA, Referenced to 25°C		20		mV/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 30 V, V_{GS} = 0 V V_{DS} = 30 V, V_{GS} = 0 V, T_J = 55°C			1 25	µA
I_{GSSF}	Gate-Body Leakage Current, Forward	V_{GS} = 20 V, V_{DS} = 0 V			100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	V_{GS} = -20 V, V_{DS} = 0 V			-100	nA
On Characteristics (Note 2)						
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS} = V_{GS}, I_D = 250 µA	1			V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 µA, Referenced to 25°C		-4		mV/°C
$R_{DS(on)}$	Static Drain-Source On-Resistance	V_{GS} = 10 V, I_D = 5.8 A V_{GS} = 10 V, I_D = 5.8 A, T_J=125°C V_{GS} = 4.5 V, I_D = 4.7 A		0.032 0.048 0.044	0.037 0.068 0.055	Ω
$I_{D(on)}$	On-State Drain Current	V_{GS} = 10 V, V_{DS} = 5 V	20			A
g_{FS}	Forward Transconductance	V_{DS} = 15 V, I_D = 5.8 A		12		S
Dynamic Characteristics						
C_{iss}	Input Capacitance	V_{DS} = 15 V, V_{GS} = 0 V, f = 1.0 MHz		460		pF
C_{oss}	Output Capacitance			115		pF
C_{rss}	Reverse Transfer Capacitance			45		pF
Switching Characteristics (Note 2)						
$t_{d(on)}$	Turn-On Delay Time	V_{DD} = 15 V, I_D = 1 A, R_L = 15 Ω V_{GS} = 10 V, R_{GEN} = 6 Ω		5	16	ns
t_r	Turn-On Rise Time			8	16	ns
$t_{d(off)}$	Turn-Off Delay Time			17	40	ns
t_f	Turn-Off Fall Time			13	35	ns
t_{rr}	Drain-Source Reverse Recovery Time	I_F = 1.7 A, di/dt = 100A/µs			80	nS
Q_g	Total Gate Charge	V_{DS} = 15 V, I_D = 5.8 A, V_{GS} = 10 V		9	25	nC
Q_{gs}	Gate-Source Charge			2		nC
Q_{gd}	Gate-Drain Charge			0.9		nC
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain-Source Diode Forward Current				1.7	A
V_{SD}	Drain-Source Diode Forward Voltage	V_{GS} = 0 V, I_S = 1.7 A (Note 2)			1.2	V

Notes:

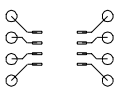
1. $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) 78° C/W when mounted on a 0.5 in² pad of 2 oz. copper.



b) 125° C/W when mounted on a 0.02 in² pad of 2 oz. copper.



c) 135° C/W when mounted on a minimum pad of 2 oz. copper.

Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width ≤ 300 µs, Duty Cycle ≤ 2.0%

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PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
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Rev. G